# 2SB1180, 2SB1180A

## Silicon PNP epitaxial planar type darlington

For medium-speed voltage switching Complementary to 2SD1750, 2SD1750A

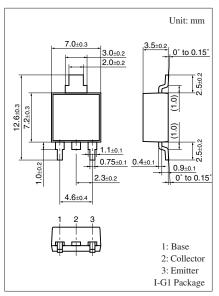
#### ■ Features

**Power Transistors** 

- High forward current transfer ratio h<sub>FE</sub>
- I type package enabling direct soldering of the radiating fin to the printed circuit board, etc. of small electronic equipment

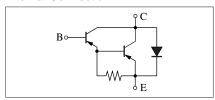
### ■ Absolute Maximum Ratings $T_C = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage	2SB1180	$V_{CBO}$	-60	V
(Emitter open)	2SB1180A		-80	
Collector-emitter voltage	2SB1180	V <sub>CEO</sub>	-60	V
(Base open)	2SB1180A		-80	
Emitter-base voltage (Col	$V_{EBO}$	-7	V	
Collector current	$I_C$	-8	A	
Peak collector current	$I_{CP}$	-12	A	
Collector power dissipation	P <sub>C</sub>	15	W	
	$T_a = 25$ °C		1.3	
Junction temperature	$T_{j}$	150	°C	
Storage temperature	$T_{stg}$	-55 to +150	°C	



Note) Self-supported type package is also prepared.

#### Internal Connection



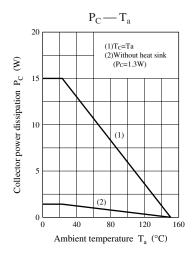
### $\blacksquare$ Electrical Characteristics $\,T_{C}=25^{\circ}C\pm3^{\circ}C$

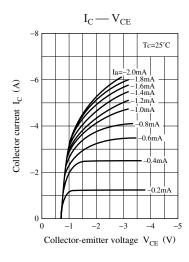
Parameter		Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage	2SB1180	V <sub>CEO</sub>	$I_C = -30 \text{ mA}, I_B = 0$	-60			V
(Base open)	2SB1180A			-80			
Collector-base cutoff	2SB1180	$I_{CBO}$	$V_{CB} = -60 \text{ V}, I_{E} = 0$			-100	μΑ
current (Emitter open)	2SB1180A		$V_{CB} = -80 \text{ V}, I_{E} = 0$			-100	
Emitter-base cutoff current (Col	lector open)	$I_{EBO}$	$V_{EB} = -7 \text{ V}, I_C = 0$			-2	mA
Forward current transfer ratio		h <sub>FE1</sub> *	$V_{CE} = -3 \text{ V}, I_{C} = -4 \text{ A}$	2000		10 000	_
		h <sub>FE2</sub>	$V_{CE} = -3 \text{ V}, I_{C} = -8 \text{ A}$	500			
Collector-emitter saturation	voltage	V <sub>CE(sat)</sub>	$I_C = -4 \text{ A}, I_B = -8 \text{ mA}$			-1.5	V
Base-emitter saturation volt	age	V <sub>BE(sat)</sub>	$I_C = -4 \text{ A}, I_B = -8 \text{ mA}$			-2	V
Transition frequency		$f_T$	$V_{CE} = -3 \text{ V}, I_{C} = -1 \text{ A}, f = 1 \text{ MHz}$		20		MHz
Turn-on time		t <sub>on</sub>	$I_C = -4 \text{ A}, I_{B1} = -8 \text{ mA}, I_{B2} = 8 \text{ mA}$		0.5		μs
Storage time		t <sub>stg</sub>	$V_{\rm CC} = -50 \text{ V}$		2.0		μs
Fall time		t <sub>f</sub>			1.0		μs

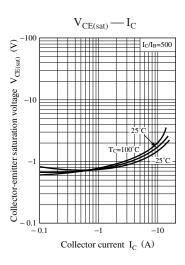
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

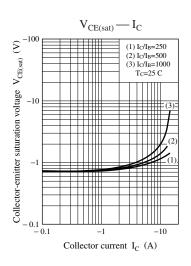
#### 2. \*: Rank classification

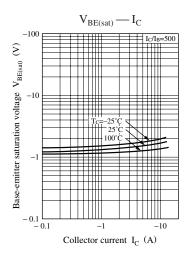
Rank	Q	Р		
h <sub>FE1</sub>	2000 to 5000	4000 to 10000		

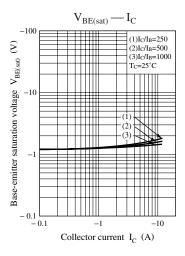


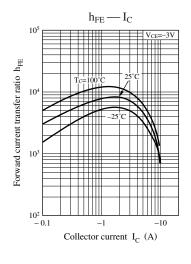


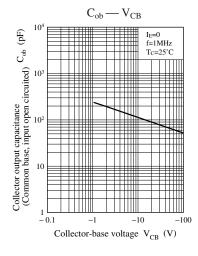


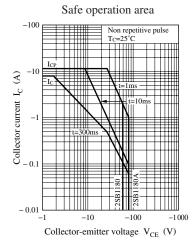


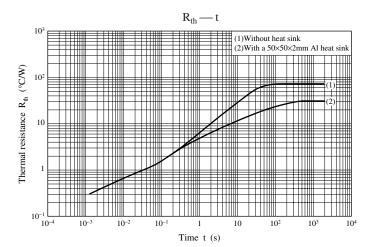












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